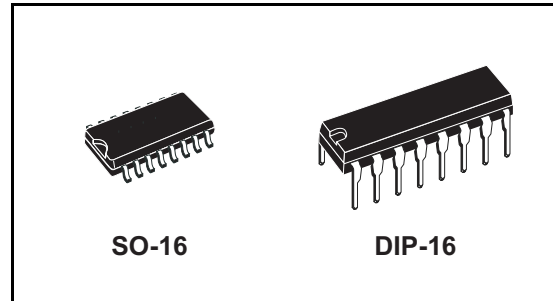


High-voltage high and low side driver

Preliminary Data

Features

- High voltage rail up to 600 V
- dV/dt immunity ± 50 V/nsec in full temperature range
- Driver current capability:
 - 270 mA source,
 - 430 mA sink
- Switching times 75/35 nsec rise/fall with 1 nF load
- 3.3 V, 5 V TTL/CMOS inputs with hysteresis
- Integrated bootstrap diode
- Operational amplifier for advanced current sensing
- Comparator for fault protections
- Smart shut down function
- Adjustable dead-time
- Interlocking function
- Compact and simplified layout
- Bill of material reduction
- Effective fault protection
- Flexible, easy and fast design



Description

The L6390 is a high-voltage device manufactured with the BCD "OFF-LINE" technology. It is a monolithic half-bridge gate driver for N-channel Power MOSFET or IGBT.

The high side (floating) section is designed to stand a voltage rail up to 600 V. The logic inputs are CMOS/TTL compatible down to 3.3 V for easy interfacing microcontroller/DSP.

The IC embeds an op amp suitable for advanced current sensing in applications such as field oriented motor control.

An integrated comparator is available for protections against over-current, over-temperature, etc.

Applications

Motor driver for home appliances, factory automation, industrial drives. HID ballasts, power supply units.

Table 1. Device summary

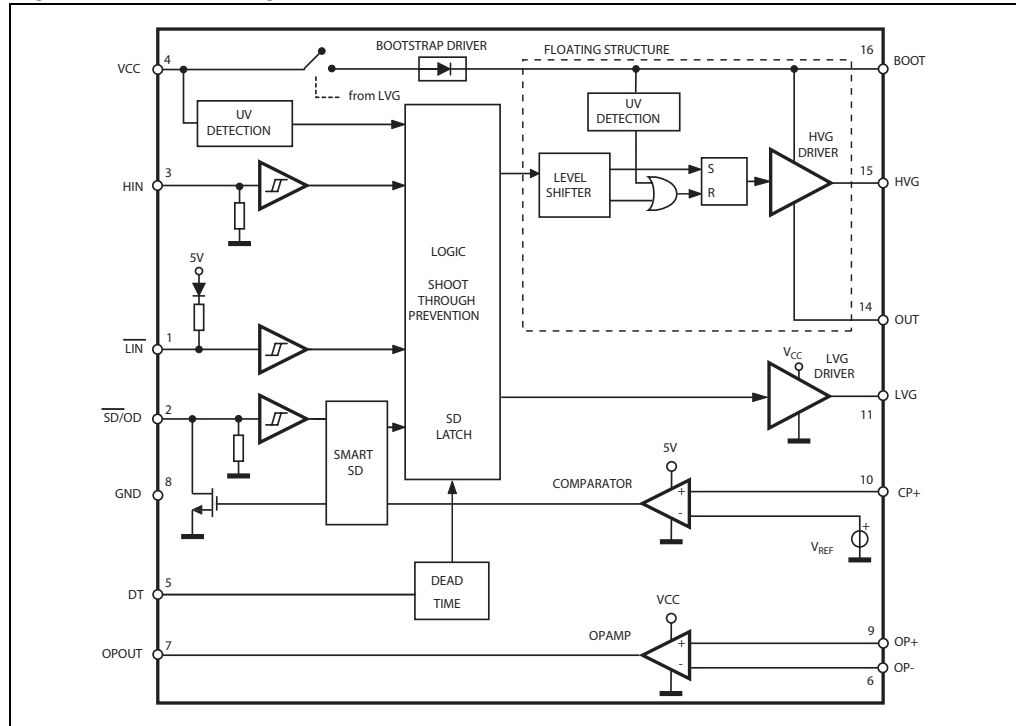
Order codes	Package	Packaging
L6390	DIP-16	Tube
L6390D	SO-16	Tube
L6390D013TR	SO-16	Tape and reel

Contents

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1 Block diagram

Figure 1. Block diagram



2 Pin connection

Figure 2. Pin connection (top view)

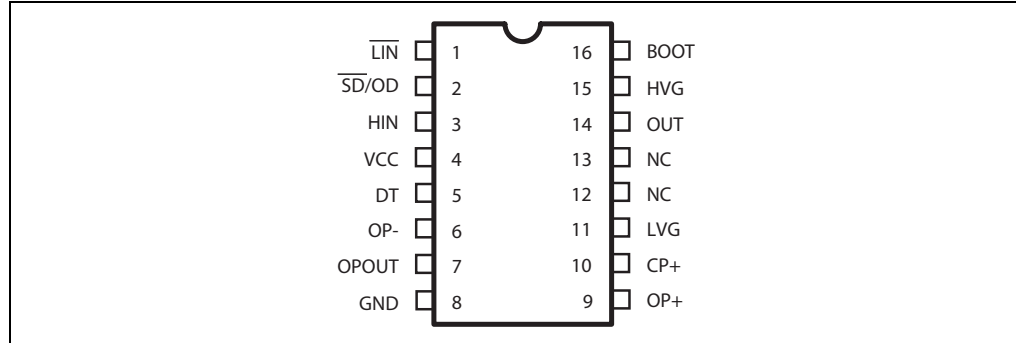


Table 2. Pin description

Pin n #	Pin name	Type	Function
1	$\overline{\text{LIN}}$	I	Low side driver logic input (active low)
2	$\overline{\text{SD/OD}}$ ⁽¹⁾	I/O	Shut down logic input (active low)/open drain (comparator output)
3	HIN	I	High side driver logic input (active high)
4	VCC	P	Lower section supply voltage
5	DT	I/O	Dead time setting
6	OP-	I	Opamp inverting input
7	OPOUT	O	Opamp output
8	GND	P	Ground
9	OP+	I	Opamp non inverting input
10	CP+	I	Comparator input
11	LVG ⁽¹⁾	O	Low side driver output
12, 13	NC		Not connected
14	OUT	P	High side (Floating) common voltage
15	HVG ⁽¹⁾	O	High side driver output
16	BOOT	P	Bootstrap supply voltage

1. (The circuit guarantees less than 1 V on the LVG and HVG pins (@ $I_{\text{sink}} = 10 \text{ mA}$), with $V_{\text{CC}} > 3 \text{ V}$. This allows omitting the "bleeder" resistor connected between the gate and the source of the external MOSFET normally used to hold the pin low; the gate driver assures low impedance also in SD condition.

3 Truth table

Table 3. Truth table

Input			Output	
\overline{SD}	\overline{LIN}	HIN	LVG	HVG
L	X	X	L	L
H	H	L	L	L
H	L	H	L	L
H	L	L	H	L
H	H	H	L	H

4 Electrical data

4.1 Absolute maximum ratings

Table 4. Absolute maximum rating

Symbol	Parameter	Value	Unit
V_{out}	Output voltage	$V_{boot} - 21$ to $V_{boot} + 0.3$	V
V_{cc}	Supply voltage	- 0.3 to + 21	V
V_{op+}	Opamp non-inverting input	-0.3 to $V_{CC} + 0.3$	V
V_{op-}	Opamp inverting input	-0.3 to $V_{CC} + 0.3$	V
V_{cp+}	Comparator input voltage	-0.3 to $V_{CC} + 0.3$	V
V_{boot}	Floating supply voltage	$V_{CC} - 0.3$ to 620	V
V_{hvg}	High side gate output voltage	$V_{out} - 0.3$ to $V_{boot} + 0.3$	V
V_{lvg}	Low side gate output voltage	-0.3 to $V_{cc} + 0.3$	V
V_i	Logic input voltage	-0.3 to 15	V
V_{od}	Open drain voltage	-0.3 to 15	V
dV_{out}/dt	Allowed output slew rate	50	V/ns
P_{tot}	Total power dissipation ($T_A = 85\text{ °C}$)	TBD	mW
T_J	Junction temperature	150	°C
T_{stg}	Storage temperature	-50 to 150	°C

Note: ESD immunity for pins 14, 15 and 16 is guaranteed up to TBD (Human Body Model)

4.2 Thermal data

Table 5. Thermal data

Symbol	Parameter	SO-16	DIP-16	Unit
$R_{th(JA)}$	Thermal resistance junction to ambient	TBD	TBD	°C/W

4.3 Recommended operating conditions

Table 6. Recommended operating conditions

Symbol	Pin	Parameter	Test condition	Min	Typ	Max	Unit
V_{out}	14	Output voltage ⁽¹⁾				580	V
$V_{BS}^{(2)}$	16	Floating supply voltage ⁽¹⁾		TBD		TBD	V
f_{sw}		Switching frequency	HVG, LVG load $C_L = 1 \text{ nF}$			800	kHz
V_{cc}	4	Supply voltage		TBD		TBD	V
T_j		Junction temperature		-40		125	°C

1. If the condition $TBD \text{ V} < V_{boot} - V_{out} < TBD \text{ V}$ and $V_{boot} < TBD \text{ V}$ are guaranteed, V_{out} can range from TBD V to 580V.

2. $V_{BS} = V_{boot} - V_{out}$

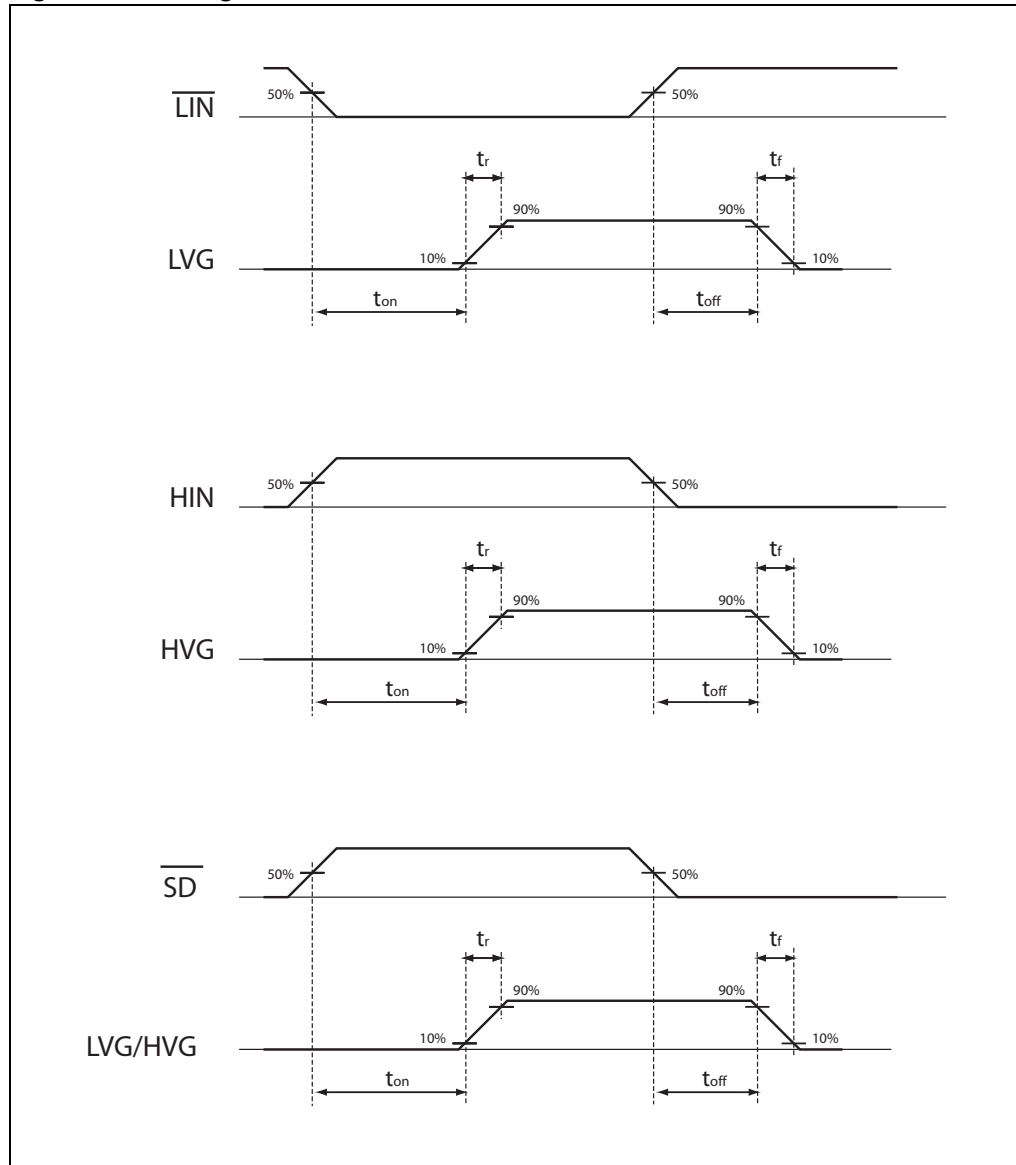
5 Electrical characteristics

5.1 AC operation

Table 7. AC operation electrical characteristics ($V_{CC} = 15\text{ V}$; $T_J = +25\text{ }^\circ\text{C}$)

Symbol	Pin	Parameter	Test condition	Min	Typ	Max	Unit
t_{on}	1 vs 11	High/low side driver turn-on propagation delay	$V_{out} = 0\text{ V}$ $V_{boot} = V_{CC}$ $C_L = 1\text{ nF}$ $V_i = 0\text{ to }3.3\text{ V}$ See Figure 3 .		125		ns
t_{off}	3 vs 15	High/low side driver turn-off propagation delay			125		ns
t_{sd}	2 vs 11, 15	Shut down to high/low side driver propagation delay			125		ns
t_{isd}		Comparator triggering to high/low side driver turn-off propagation delay	Measured applying a voltage step from 0V to 3.3 V to pin CP+.		180		ns
MT		Delay matching, HS and LS turn-on/off				40	ns
dt	5	Dead time setting range	$R_{dt} = 0, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$		0.15		μs
			$R_{dt} = 37\text{ k}\Omega, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$		0.5		μs
			$R_{dt} = 136\text{ k}\Omega, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$		1.5		μs
			$R_{dt} = 260\text{ k}\Omega, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$		2.8		μs
MDT	5	Matching dead time	$R_{dt} = 0, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$			60	ns
			$R_{dt} = 37\text{ k}\Omega, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$			TBD	ns
			$R_{dt} = 136\text{ k}\Omega, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$			TBD	ns
			$R_{dt} = 260\text{ k}\Omega, C_L = 1\text{ nF}, C_{DT} = 100\text{ nF}$			TBD	ns
t_r	11, 15	Rise time	$C_L = 1\text{ nF}$		75		ns
t_f		Fall time	$C_L = 1\text{ nF}$		35		ns

Figure 3. Timing



5.2 DC operation

Table 8. DC operation electrical characteristics ($V_{CC} = 15\text{ V}$; $T_J = +25\text{ }^\circ\text{C}$)

Symbol	Pin	Parameter	Test condition	Min	Typ	Max	Unit	
Low supply voltage section								
V_{CC_hys}	4	V_{CC} UV hysteresis		700	1400		mV	
V_{CC_thON}		V_{CC} UV turn ON threshold			11.8		V	
V_{CC_thOFF}		V_{CC} UV turn OFF threshold			10.4		V	
I_{qccu}		Undervoltage quiescent supply current	$V_{CC} = 10\text{ V}$ $\overline{SD} = 5\text{ V}$; $\overline{LIN} = 5\text{ V}$ and $HIN = GND$; $R_{DT} = 0\ \Omega$; $CP+=OP+=GND$; $OP-=5\text{ V}$			120	150	μA
I_{qcc}		Quiescent current	$V_{CC} = 15\text{ V}$ $\overline{SD} = 5\text{ V}$; $\overline{LIN} = 5\text{ V}$ and $HIN = GND$; $R_{DT} = 0\ \Omega$; $CP+=OP+=GND$; $OP-=5\text{ V}$			720	1100	μA
V_{ref}		Internal reference voltage			0.53		V	
Bootstrapped supply voltage section								
V_{BS_hys}	16	V_{BS} UV hysteresis		700	1400		mV	
V_{BS_thON}		V_{BS} UV turn ON threshold			11.6		V	
V_{BS_thOFF}		V_{BS} UV turn OFF threshold			10.2		V	
I_{QBSU}		Undervoltage V_{BS} quiescent current	$V_{BS} = 10\text{ V}$ $\overline{SD} = 5\text{ V}$; \overline{LIN} and $HIN = 5\text{ V}$; $R_{DT} = 0\ \Omega$; $CP+=OP+=GND$; $OP-=5\text{ V}$			70	110	μA
I_{QBS}		V_{BS} quiescent current	$V_{BS} = 15\text{ V}$ $\overline{SD} = 5\text{ V}$; \overline{LIN} and $HIN = 5\text{ V}$; $R_{DT} = 0\ \Omega$; $CP+=OP+=GND$; $OP-=5\text{ V}$			152	μA	
I_{LK}		High voltage leakage current	$V_{hvg} = V_{out} = V_{boot} = 600\text{ V}$			10	μA	
$R_{dson}^{(1)}$		Bootstrap driver on resistance	LVG ON			120	Ω	
Driving buffers section								
I_{so}	11	High/low side source short circuit current	$V_{IN} = V_{ih}$ ($t_p < 10\ \mu\text{s}$)			270	mA	
I_{si}	15	High/low side sink short circuit current	$V_{IN} = V_{il}$ ($t_p < 10\ \mu\text{s}$)			430	mA	

Table 8. DC operation electrical characteristics ($V_{CC} = 15\text{ V}$; $T_J = +25\text{ }^\circ\text{C}$) (continued)

Symbol	Pin	Parameter	Test condition	Min	Typ	Max	Unit
Logic inputs							
V_{il}	1, 2, 3	Low level logic threshold voltage				0.83	V
V_{ih}		High level logic threshold voltage		2.21			V
I_{HINh}	3	HIN logic "1" input bias current	HIN = 15 V		175	260	μA
I_{HINl}		HIN logic "0" input bias current	HIN = 0 V			1	μA
I_{LINh}	1	$\overline{\text{LIN}}$ logic "1" input bias current	$\overline{\text{LIN}} = 0\text{ V}$		6	40	μA
I_{LINl}		$\overline{\text{LIN}}$ logic "0" input bias current	$\overline{\text{LIN}} = 15\text{ V}$			1	μA
I_{SDh}	2	$\overline{\text{SD}}$ logic "1" input bias current	$\overline{\text{SD}} = 15\text{ V}$		30	100	μA
I_{SDl}		$\overline{\text{SD}}$ logic "0" input bias current	$\overline{\text{SD}} = 0\text{ V}$			1	μA

1. R_{DSON} is tested in the following way:

$$R_{\text{DSON}} = [(V_{\text{CC}} - V_{\text{CBOOT1}}) - (V_{\text{CC}} - V_{\text{CBOOT2}})] / [I_1(V_{\text{CC}}, V_{\text{CBOOT1}}) - I_2(V_{\text{CC}}, V_{\text{CBOOT2}})]$$

where I_1 is pin 16 current when $V_{\text{CBOOT}} = V_{\text{CBOOT1}}$, I_2 when $V_{\text{CBOOT}} = V_{\text{CBOOT2}}$.

Table 9. OPAMP characteristics ($V_{CC} = 15\text{ V}$, $T_J = +25\text{ }^\circ\text{C}$)

Symbol	Pin	Parameter	Test condition	Min	Typ	Max	Unit
V_{io}	6, 9	Input offset voltage	$V_O = \text{TBD}$; $0 < V_{icm} < V_{CC} - \text{TBD}$			3	mV
I_{ib}		Input bias current ⁽¹⁾			15	200	nA
V_{icm}		Input common mode voltage range		0		$V_{CC} - \text{TBD}$	
V_{OL}	7	Output voltage swing - low level	$I_{sink} = 3.5\text{ mA}$, $R_L = 2\text{ k}\Omega$		180	360	mV
V_{OH}		Output voltage swing - high level	$I_{source} = 3.5\text{ mA}$, $R_L = 2\text{ k}\Omega$	13.5	14.3		V
I_o		Output short circuit current	Source, $V_{id} = \text{TBD}$; $V_o = \text{TBD}$	16	30		mA
	Sink $V_{id} = \text{TBD}$; $V_o = \text{TBD}$		50	80		mA	
SR		Slew rate	$V_i = \text{TBD}$; $R_L = 2\text{ k}\Omega$; $C_L = \text{TBD}$; unity gain	2.5	3.8		V/ μs
GBWP		Gain bandwidth product	$V_o = \text{TBD}$; $R_L = 2\text{ k}\Omega$		TBD		MHz
A_{vd}		Large signal voltage gain		85	95		dB
SRV		Power supply rejection ratio	vs V_{CC}		85		dB
CMRR		Common mode rejection ratio		80	100		dB

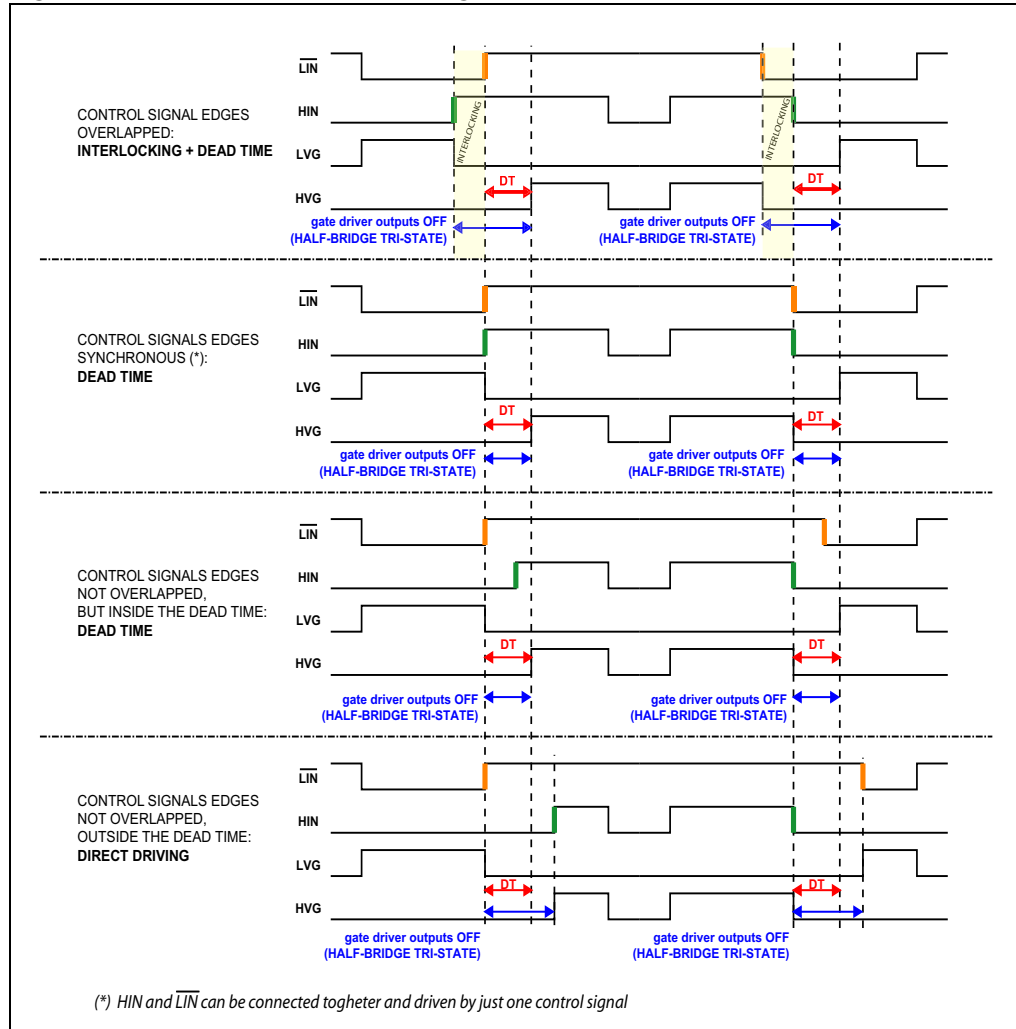
1. The direction of input current is out of the IC.

Table 10. Sense comparator characteristics ($V_{CC} = 15\text{ V}$, $T_J = +25\text{ }^\circ\text{C}$)

Symbol	Pin	Parameter	Test conditions	Min	Typ	Max	Unit
I_{io}	10	Input bias current	$V_{CP+} = 1\text{ V}$			1	μA
V_{ol}	2	Open drain low level output voltage	$I_{od} = -3\text{ mA}$			0.5	V
t_{d_comp}		Comparator delay	\overline{SD}/OD pulled to 5 V through 100 k Ω resistor		115	210	ns
SR		Slew rate	$C_L = 180\text{ nF}$; $R_{pu} = 5\text{ k}\Omega$		60		V/ μsec

6 Waveforms definitions

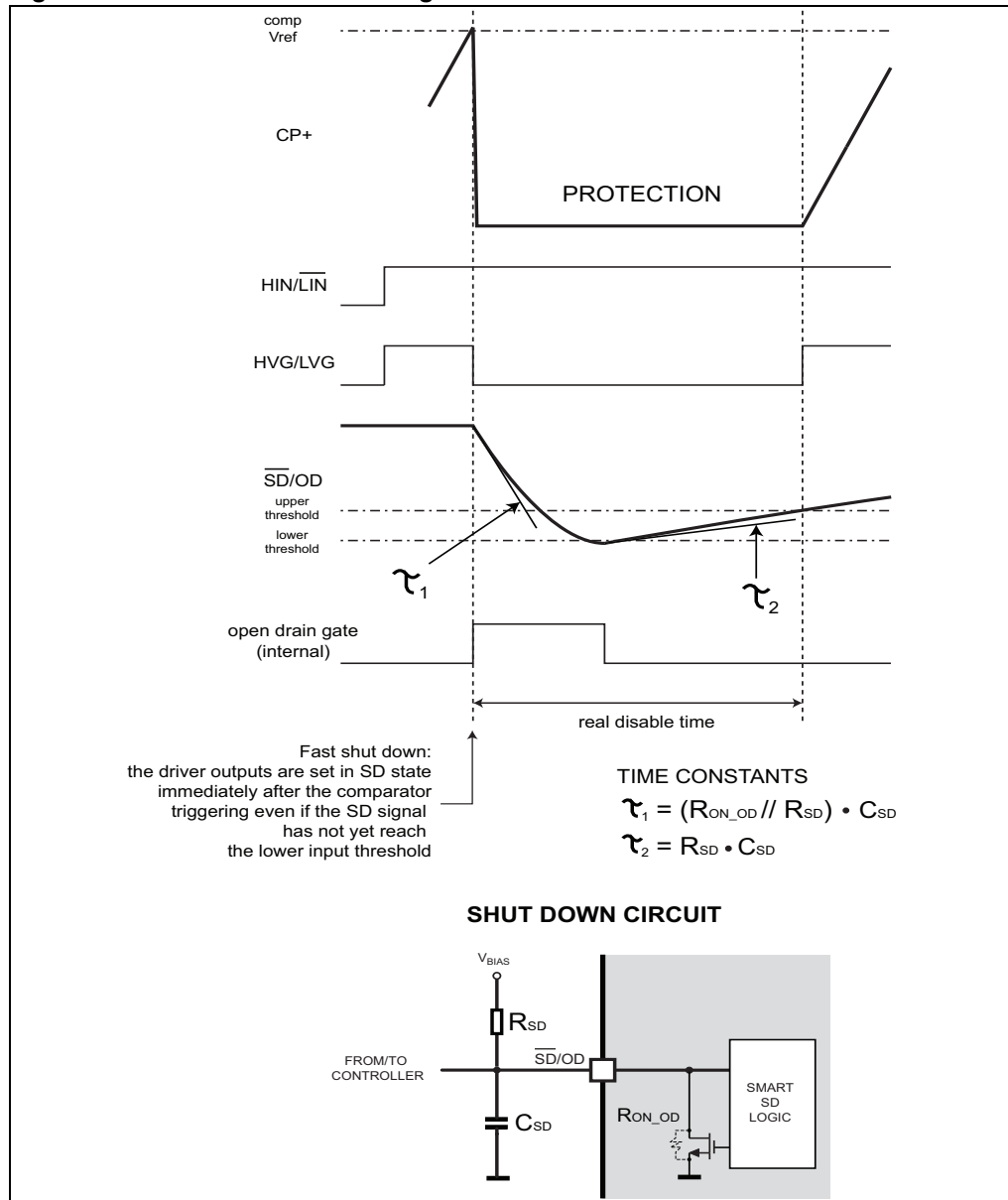
Figure 4. Dead time and interlocking waveforms definitions



7 Smart shut down function

L6390 integrates a comparator committed to the fault sensing function. The comparator has an internal voltage reference V_{ref} connected to its inverting input, while the non-inverting input is available on pin 10. The comparator input can be connected to an external shunt resistor in order to implement a simple over-current detection function. The output signal of the comparator is fed to an integrated MOSFET which open drain is available on pin 2, shared with the SD input. When the comparator triggers, the device is set in shut down state and both its outputs are set to low level leaving the half-bridge in tri-state.

Figure 5. Smart shut down timing waveforms

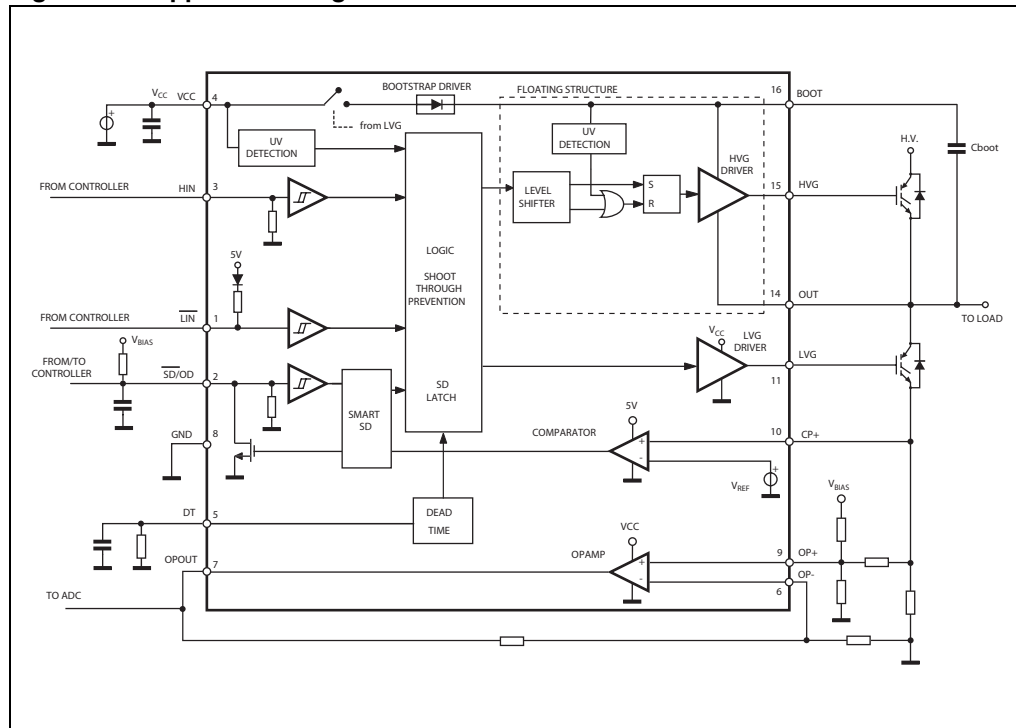


In common over-current protection architectures the comparator output is usually connected to the SD input and an RC network is connected to this SD/OD line in order to provide a mono-stable circuit, which implements a protection time that follows the fault condition. Differently from the common fault detection systems, L6390 Smart Shut Down architecture allows to immediately turn-off the output gate driver in case of fault, by minimizing the propagation delay between the fault detection event and the actual outputs switch-off. In fact the time delay between the fault and outputs disabling is not dependent on the RC value of the external network connected to the pin but, thanks to the Smart Shut Down logic, it has a preferential path in the IC immediately turning-OFF the driver outputs and latching the turn-ON of the open drain switch until the SD signal has reached the input pin lower threshold. After the SD signal goes below the lower threshold, the open drain is switched off. The Smart SD system provides the possibility to increase the time constant of the external RC network (that is the disable time after the fault event) up to very large values without compromising the intervention time of the protection.

An external signal provided to the SD pin is not latched and can be used as control signal in order to perform, for instance, PWM chopping through this pin. In fact when a PWM signal is applied to the SD input and the logic inputs of the gate driver are stable, the outputs switch from the low level to the state defined by the logic inputs and vice versa.

8 Typical application diagram

Figure 6. Application diagram



9 Bootstrap driver

A bootstrap circuitry is needed to supply the high voltage section. This function is normally accomplished by a high voltage fast recovery diode (*Figure 7.a*). In the L6390 a patented integrated structure replaces the external diode. It is realized by a high voltage DMOS, driven synchronously with the low side driver (LVG), with diode in series, as shown in *Figure 7.b*.

An internal charge pump (*Figure 7.b*) provides the DMOS driving voltage.

9.1 C_{BOOT} selection and charging

To choose the proper C_{BOOT} value the external MOS can be seen as an equivalent capacitor. This capacitor C_{EXT} is related to the MOS total gate charge:

Equation 1

$$C_{EXT} = \frac{Q_{gate}}{V_{gate}}$$

The ratio between the capacitors C_{EXT} and C_{BOOT} is proportional to the cyclical voltage loss. It has to be:

Equation 2

$$C_{BOOT} \gg \gg C_{EXT}$$

e.g.: if Q_{gate} is 30 nC and V_{gate} is 10 V, C_{EXT} is 3 nF. With C_{BOOT} = 100 nF the drop would be 300 mV.

If HVG has to be supplied for a long time, the C_{BOOT} selection has to take into account also the leakage and quiescent losses.

e.g.: HVG steady state consumption is lower than 200 μA, so if HVG T_{ON} is 5 ms, C_{BOOT} has to supply 1 μC to C_{EXT}. This charge on a 1 μF capacitor means a voltage drop of 1V.

The internal bootstrap driver gives a great advantage: the external fast recovery diode can be avoided (it usually has great leakage current).

This structure can work only if V_{OUT} is close to GND (or lower) and in the meanwhile the LVG is on. The charging time (T_{charge}) of the C_{BOOT} is the time in which both conditions are fulfilled and it has to be long enough to charge the capacitor.

The bootstrap driver introduces a voltage drop due to the DMOS R_{DSON} (typical value: 125 Ω). At low frequency this drop can be neglected. Anyway increasing the frequency it must be taken in to account.

The following equation is useful to compute the drop on the bootstrap DMOS:

Equation 3

$$V_{\text{drop}} = I_{\text{charge}} R_{\text{dson}} \rightarrow V_{\text{drop}} = \frac{Q_{\text{gate}}}{T_{\text{charge}}} R_{\text{dson}}$$

where Q_{gate} is the gate charge of the external power MOS, R_{dson} is the on resistance of the bootstrap DMOS and T_{charge} is the charging time of the bootstrap capacitor.

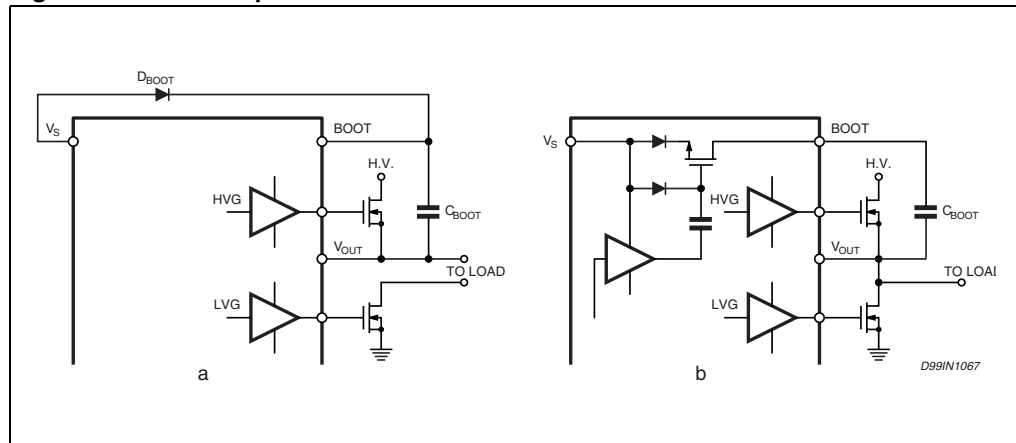
For example: using a power MOS with a total gate charge of 30nC the drop on the bootstrap DMOS is about 1V, if the T_{charge} is 5µs. In fact:

Equation 4

$$V_{\text{drop}} = \frac{30\text{nC}}{5\mu\text{s}} \cdot 125\Omega \sim 0.8\text{V}$$

V_{drop} has to be taken into account when the voltage drop on C_{BOOT} is calculated: if this drop is too high, or the circuit topology doesn't allow a sufficient charging time, an external diode can be used.

Figure 7. Bootstrap driver



10 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

Figure 8. DIP-16 mechanical data and package dimensions

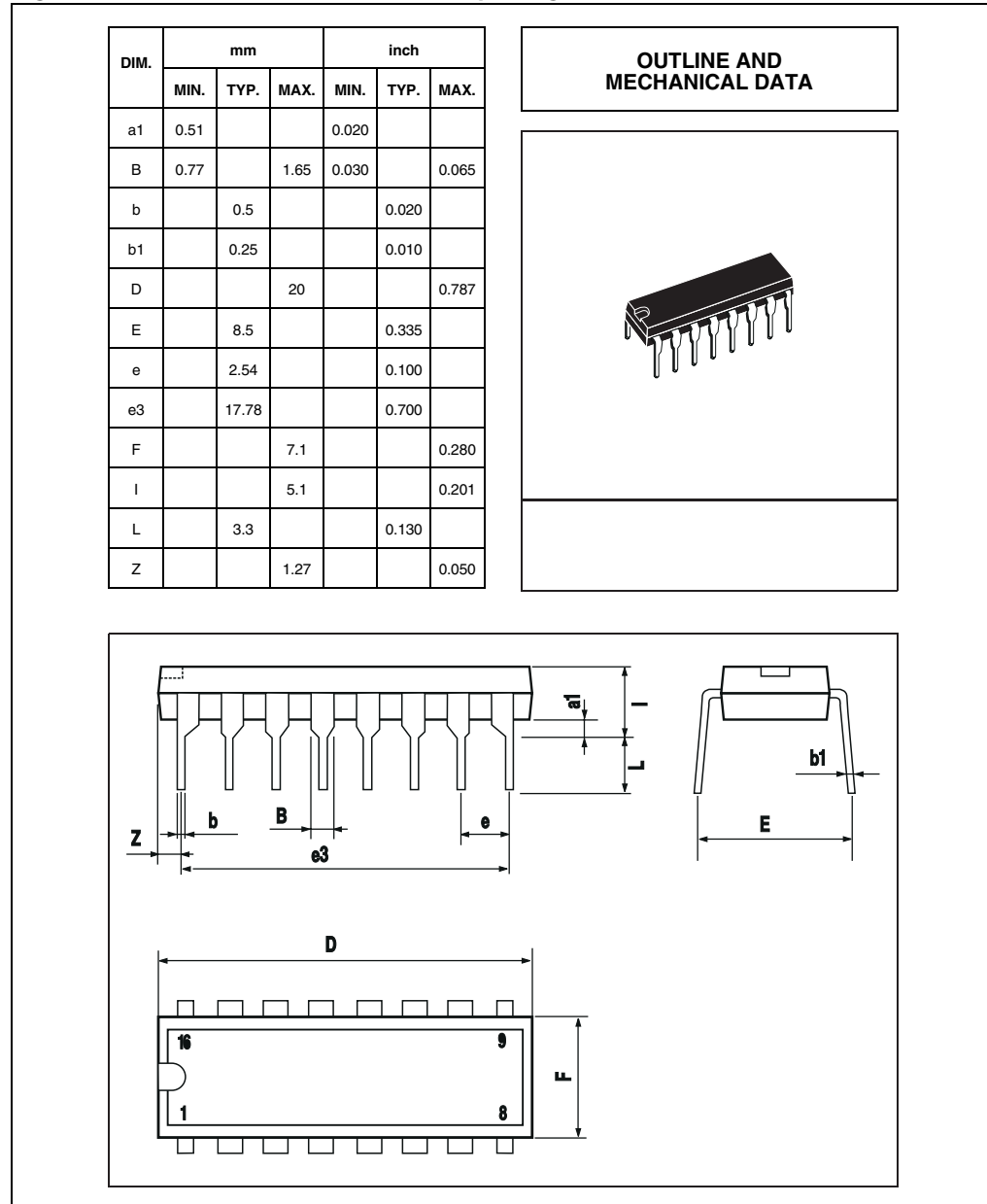
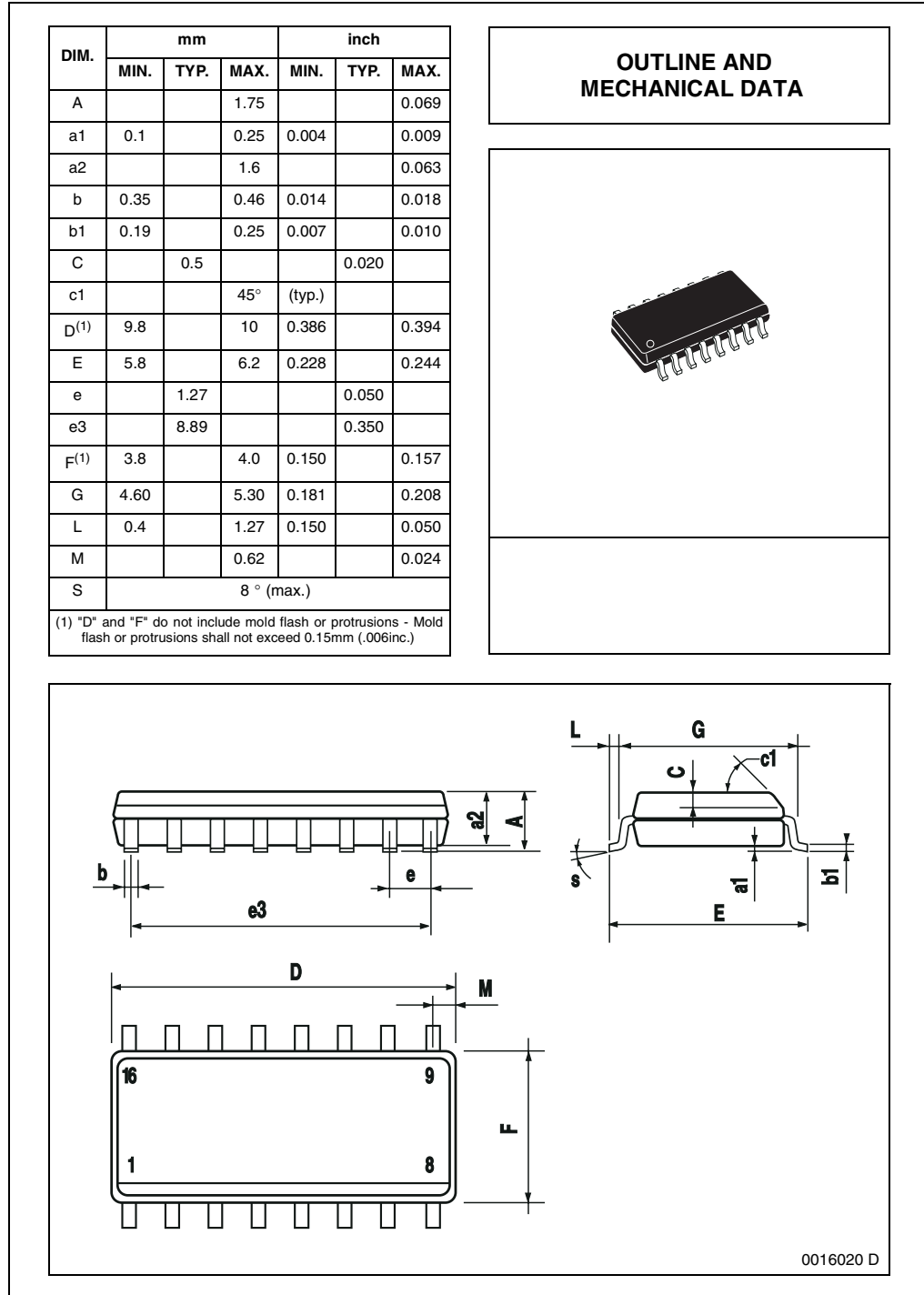


Figure 9. SO-16 narrow mechanical data and package dimensions



11 Revision history

Table 11. Document revision history

Date	Revision	Changes
29-Feb-2008	1	First release

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